



• General Description

It combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. It combines one N channel MOSFET and one P channel MOSFET

• Features

- AEC-Q101 Qualified
- Low $R_{DS(ON)}$ to minimize conductive loss
- Dual DIE in one package
- Low Thermal resistance

• Application

- BLDC Motor driver
- Load switch

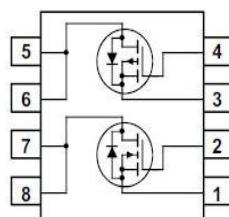
• Ordering Information:

Part NO.	ZMCA88601S
Marking	ZMC88601
Packing Information	REEL TAPE
Basic ordering unit (pcs)	4000

• N Channel Absolute Maximum Ratings ($T_C=25^\circ\text{C}$)

Parameter	Symbol	Conditions	Value	Unit
Drain-Source Voltage	V_{DS}		60	V
Gate-Source Voltage ^①	V_{GS}		± 20	V
Continuous Drain Current	I_D	$T_C=25^\circ\text{C}$	4.5	A
	I_D	$T_C=75^\circ\text{C}$	4	A
	I_D	$T_C=100^\circ\text{C}$	3	A
Pulsed Drain Current	I_{DM}	Pulsed; $t_p \leq 10 \mu\text{s}$; $T_{mb} = 25^\circ\text{C}$	13.5	A
Total Power Dissipation	P_D	$T_C=25^\circ\text{C}$	4	W
Total Power Dissipation	P_D	$T_A=25^\circ\text{C}$	0.7	W
Operating Junction Temperature	T_J		-55 to +150	$^\circ\text{C}$
Storage Temperature	T_{STG}		-55 to +150	$^\circ\text{C}$
Single Pulse Avalanche Energy	E_{AS}	$L=0.1\text{mH}$, $V_{GS}=10\text{V}$, $R_g=25\Omega$,	10	mJ
		$L=0.5\text{mH}$, $V_{GS}=10\text{V}$, $R_g=25\Omega$,	21	mJ
ESD Level (HBM)			CLASS 1C	

• Product Summary



$V_{DS1} = 60\text{V}$

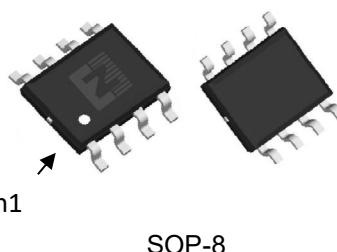
$V_{DS2} = -60\text{V}$

$R_{DS(ON)1} = 43\text{m}\Omega$

$R_{DS(ON)2} = 57\text{m}\Omega$

$I_{D1} = 4.5\text{A}$

$I_{D2} = -4\text{A}$



•P Channel Absolute Maximum Ratings ($T_C=25^\circ\text{C}$)

Parameter	Symbol	Conditions	Value	Unit
Drain-Source Voltage	V_{DS}		-60	V
Gate-Source Voltage ^②	V_{GS}		± 20	V
Continuous Drain Current	I_D	$T_C=25^\circ\text{C}$	-4	A
	I_D	$T_C=75^\circ\text{C}$	-4	A
	I_D	$T_C=100^\circ\text{C}$	-3	A
Pulsed Drain Current	I_{DM}	Pulsed; $t_p \leq 10 \mu\text{s}$; $T_{mb} = 25^\circ\text{C}$	-12	A
Total Power Dissipation	P_D	$T_C=25^\circ\text{C}$	4	W
Total Power Dissipation	P_D	$T_A=25^\circ\text{C}$	0.7	W
Operating Junction Temperature	T_J		-55 to +150	$^\circ\text{C}$
Storage Temperature	T_{STG}		-55 to +150	$^\circ\text{C}$
Single Pulse Avalanche Energy	E_{AS}	$L=0.1\text{mH}$, $V_{GS}=-10\text{V}$, $R_g=25\Omega$,	30	mJ
		$L=0.5\text{mH}$, $V_{GS}=-10\text{V}$, $R_g=25\Omega$,	54	mJ
ESD Level (HBM)			CLASS 2	

•Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R_{thJC}		-	34	$^\circ\text{C/W}$
Thermal resistance, junction-ambient ^③	R_{thJA}		-	180	$^\circ\text{C/W}$
Soldering temperature	T_{sold}		-	260	$^\circ\text{C}$



•N Channel Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	60			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	1.2	1.7	2.5	V
Drain-Source Leakage Current	I_{DSS}	$V_{GS}=0V, V_{DS}= 60V$			1.0	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS} = 0V$			100	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D= 4.5A$		43	50	$m\Omega$
		$V_{GS}=4.5V, I_D= 4A$		75	85	$m\Omega$
Forward Transconductance	g_{FS}	$V_{DS} = 5V, I_{SD} = 2A$		10		s
Diode Forward Voltage	V_{FSD}	$V_{GS} = 0V, I_{SD} = 4.5A$			1.3	V

•N Channel Dynamic characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$f = 1MHz, V_{DS}=25V$	-	823	-	pF
Output capacitance	C_{oss}		-	33	-	
Reverse transfer capacitance	C_{rss}		-	19	-	
Gate Resistance	R_g	$f = 1MHz$	-	1		Ω
Total gate charge	Q_g	$V_{DD} = 25V, I_D = 3A, V_{GS} = 10V$	-	12	-	nC
	$Q_g (4.5v)$		-	5	-	
Gate - Source charge	Q_{gs}		-	1.6	-	
Gate - Drain charge	Q_{gd}		-	2.6	-	
Turn-ON Delay time	$t_{D(on)}$		-	2	-	ns
Turn-ON Rise time	t_r	$V_{GS}=10V, V_{DS}=15V, R_G = 3.3\Omega, I_D = 20A$	-	3	-	ns
Turn-Off Delay time	$t_{D(off)}$		-	10	-	ns
Turn-Off Fall time	t_f		-	7.5	-	ns



•P Channel Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = -250\mu A$	-60			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = -250\mu A$	-1.2	-1.7	-2.5	V
Drain-Source Leakage Current	I_{DSS}	$V_{GS}=0V, V_{DS} = -60V$			1.0	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS} = 0V$			100	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS}=-10V, I_D = -4A$		57	74	$m\Omega$
		$V_{GS}=-4.5V, I_D = -3A$		76	100	$m\Omega$
Forward Transconductance	g_{FS}	$V_{DS} = -5V, I_{SD} = -2A$		9		s
Diode Forward Voltage	V_{FSD}	$V_{GS} = 0V, I_{SD} = -4A$			1.3	V

•P Channel Dynamic characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$f = 1MHz, V_{DS}=-25V$	-	1380	-	pF
Output capacitance	C_{oss}		-	101	-	
Reverse transfer capacitance	C_{rss}		-	67	-	
Gate Resistance	R_g	$f = 1MHz$	-	8		Ω
Total gate charge	Q_g	$V_{DD} = -25V, I_D = -3A, V_{GS} = -10V$	-	21	-	nC
	$Q_g (-4.5v)$		-	9	-	
Gate - Source charge	Q_{gs}		-	3.5	-	
Gate - Drain charge	Q_{gd}		-	3.6	-	
Turn-ON Delay time	$t_{D(on)}$	$V_{GS}=-10V, V_{DS}=-15V, R_G = 3.3, I_D = -10A$	-	20	-	ns
Turn-ON Rise time	t_r		-	174	-	ns
Turn-Off Delay time	$t_{D(off)}$		-	43	-	ns
Turn-Off Fall time	t_f		-	10.4	-	ns

• N Channel characteristics curve

Fig.1 Gate-Charge Characteristics

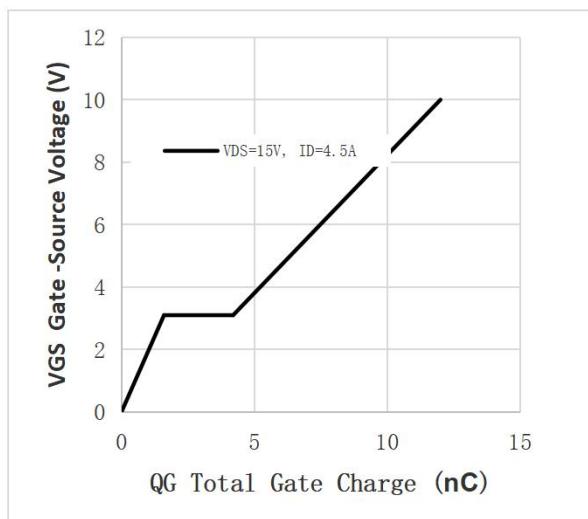


Fig.2 Capacitance Characteristics

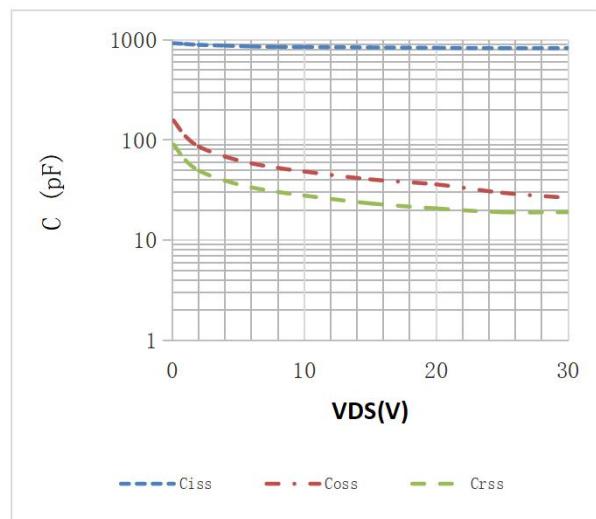


Fig.3 Power Dissipation

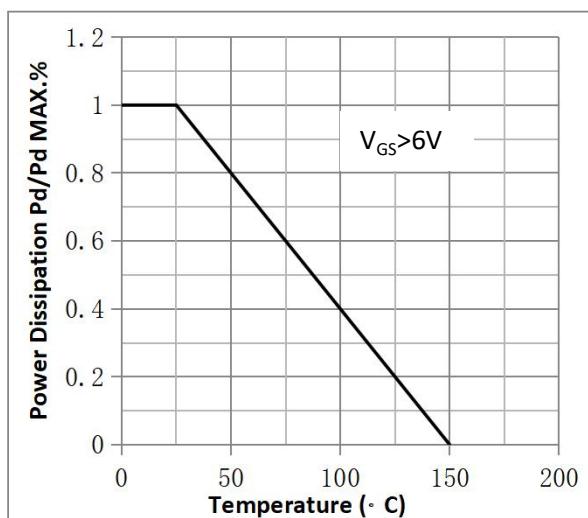


Fig.4 Typical output Characteristics

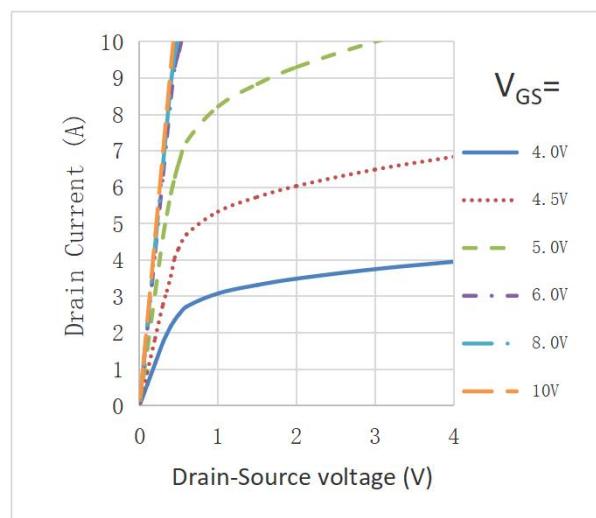


Fig.5 Threshold Voltage V.S Junction Temperature

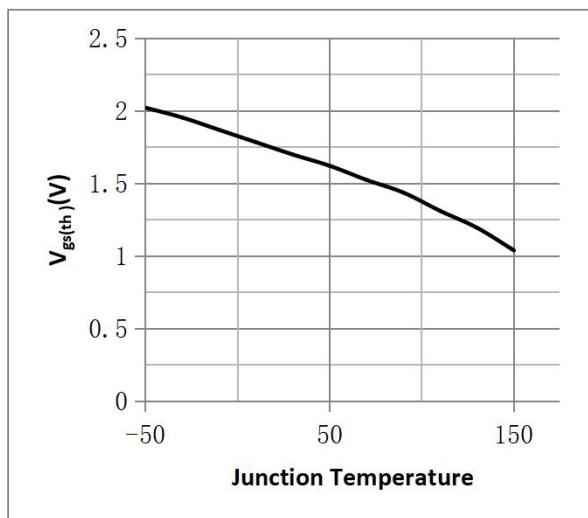


Fig.6 Resistance V.S Drain Current

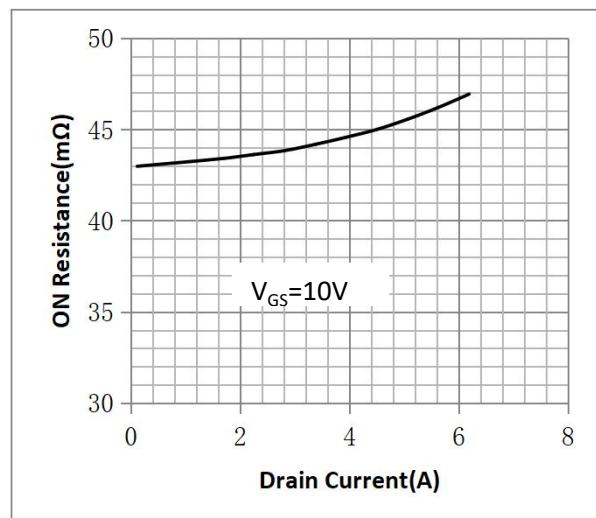


Fig.7 On-Resistance VS Gate Source Voltage

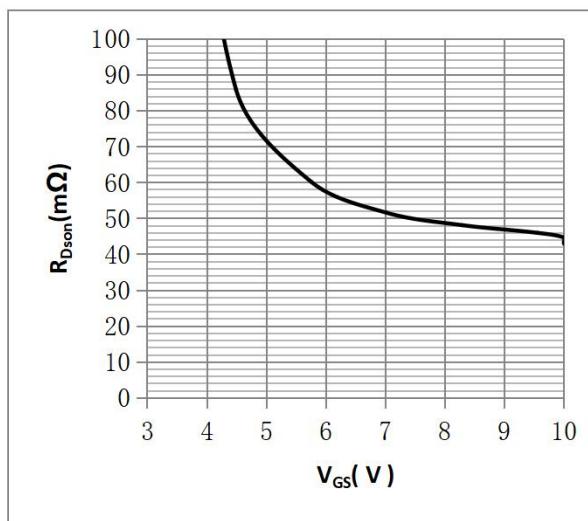


Figure 9. Diode Forward Voltage vs. Current

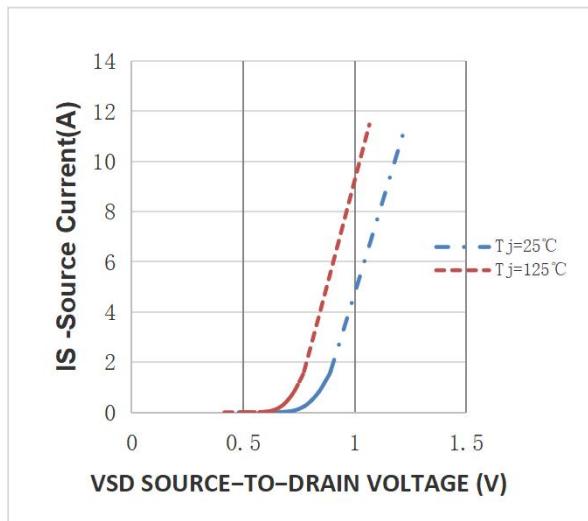


Fig.11 Safe Operating Area

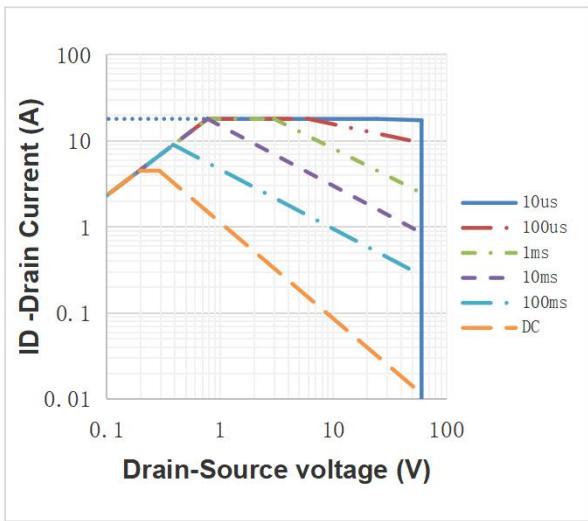


Fig.8 On-Resistance V.S Junction Temperature

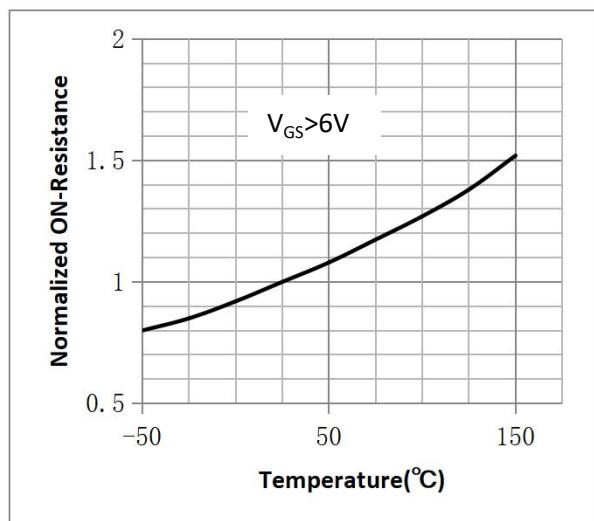
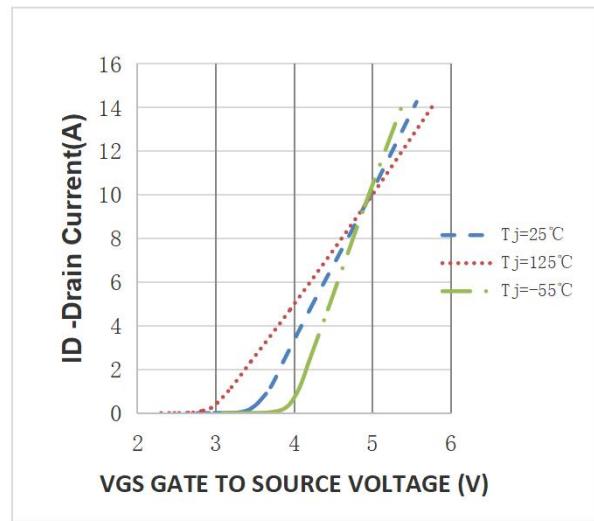
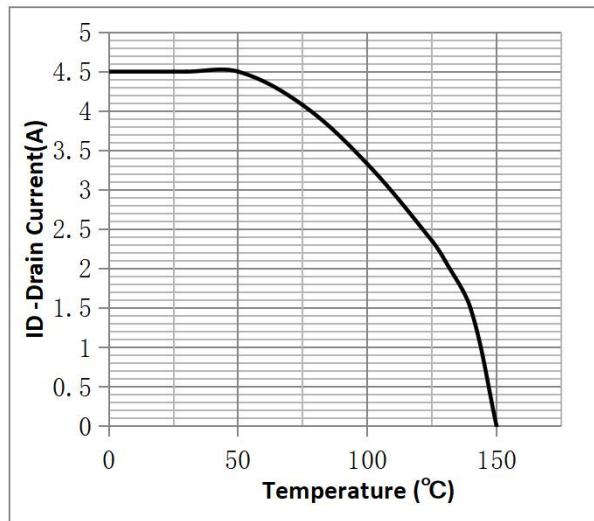


Figure 10. Transfer Characteristics

Fig.12 ID vs. Case Temperature^④

•p Channel characteristics curve

Fig.1 Gate-Charge Characteristics

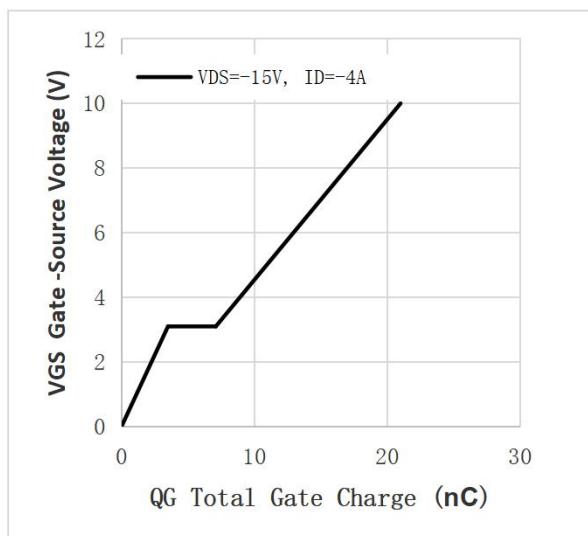


Fig.2 Capacitance Characteristics

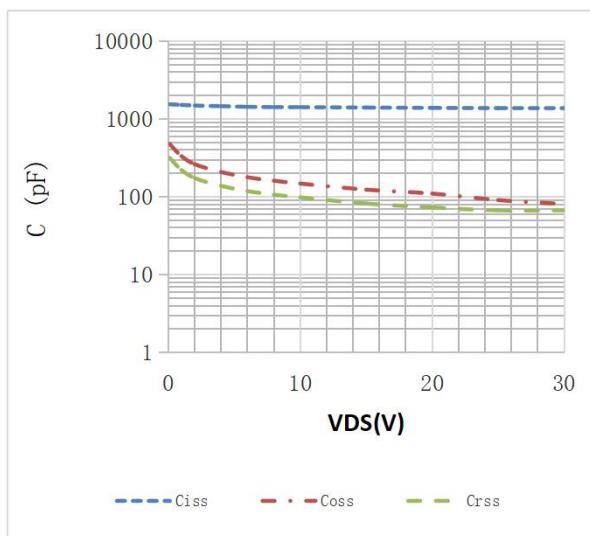


Fig.3 Power Dissipation

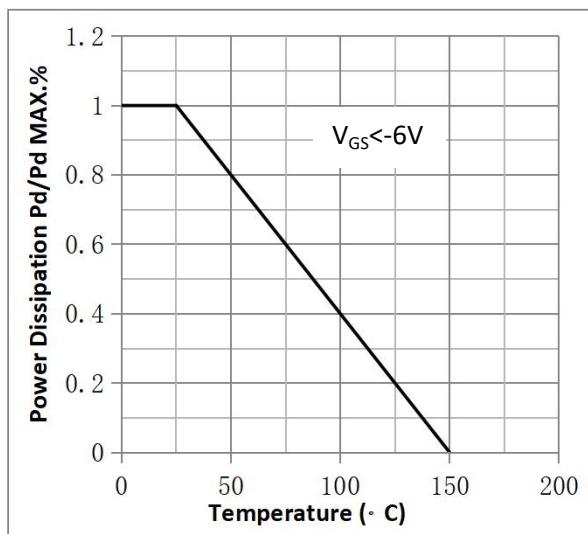


Fig.4 Typical output Characteristics

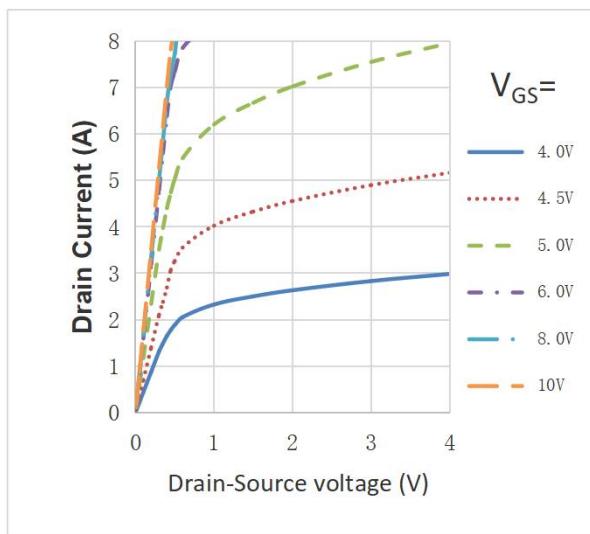


Fig.5 Threshold Voltage V.S Junction Temperature

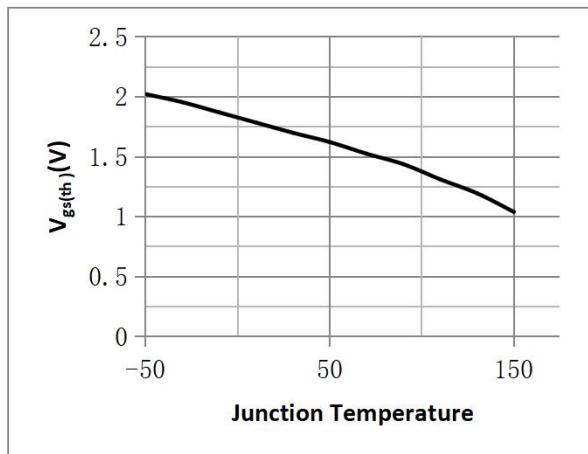


Fig.6 Resistance V.S Drain Current

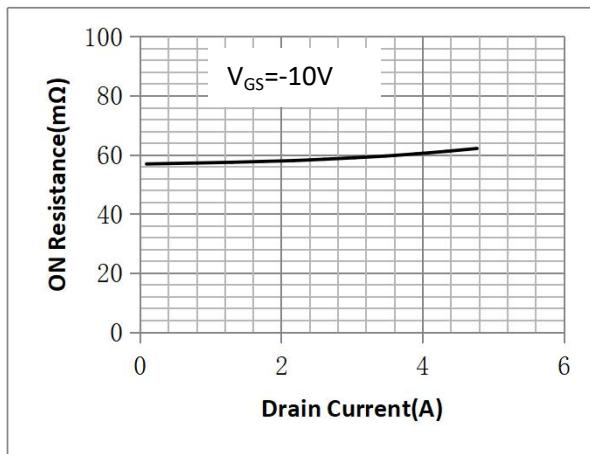


Fig.7 On-Resistance VS Gate Source Voltage

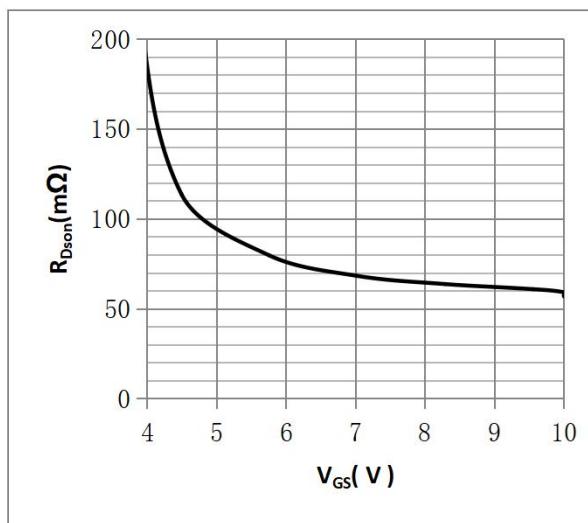


Fig.8 On-Resistance V.S Junction Temperature

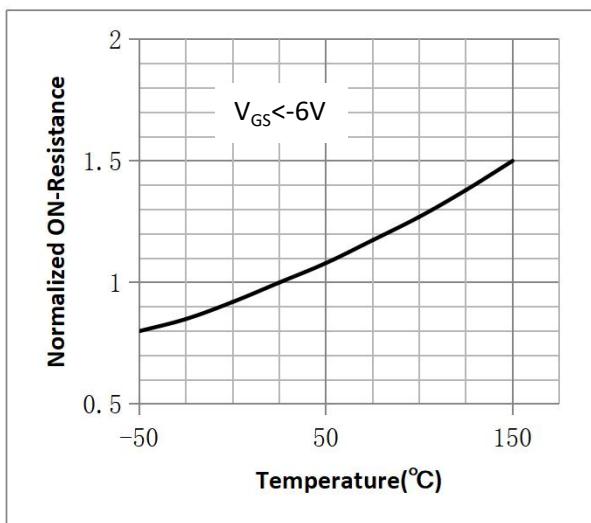


Figure 9. Diode Forward Voltage vs. Current

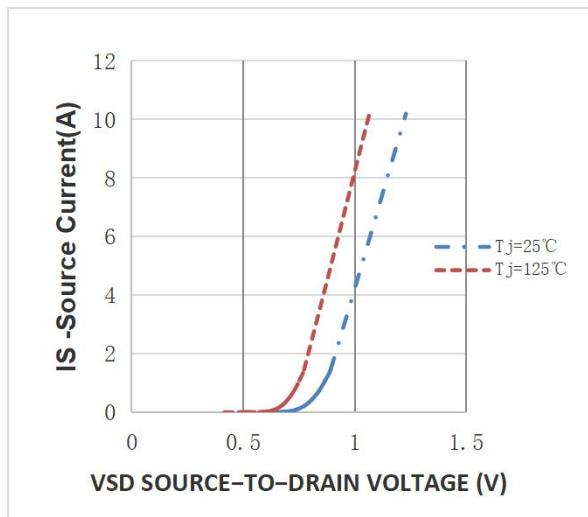


Figure 10. Transfer Characteristics

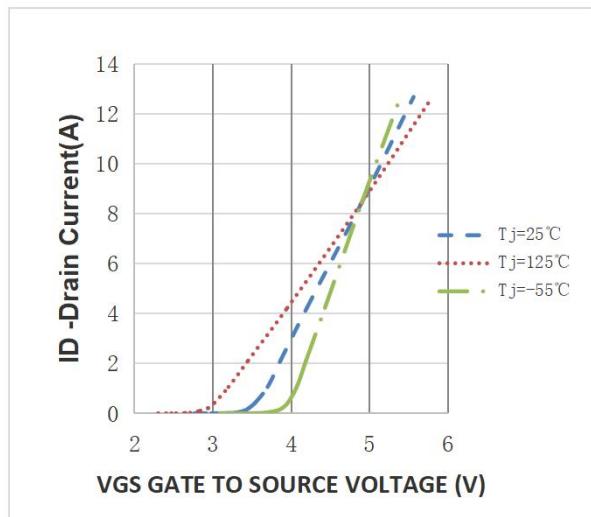
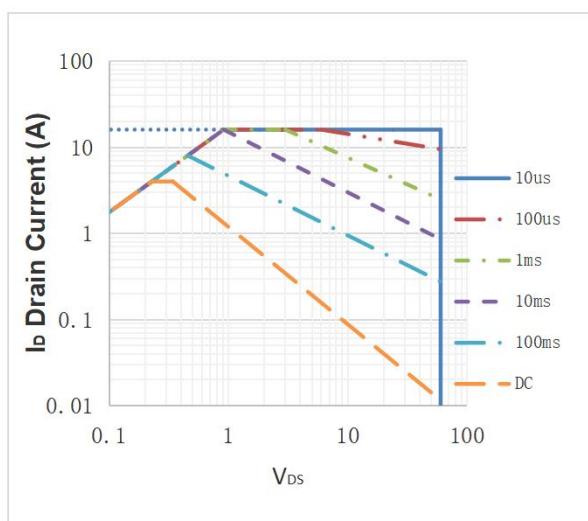
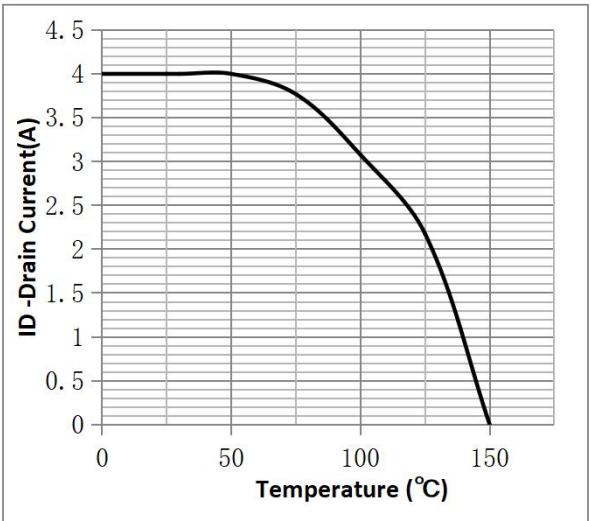
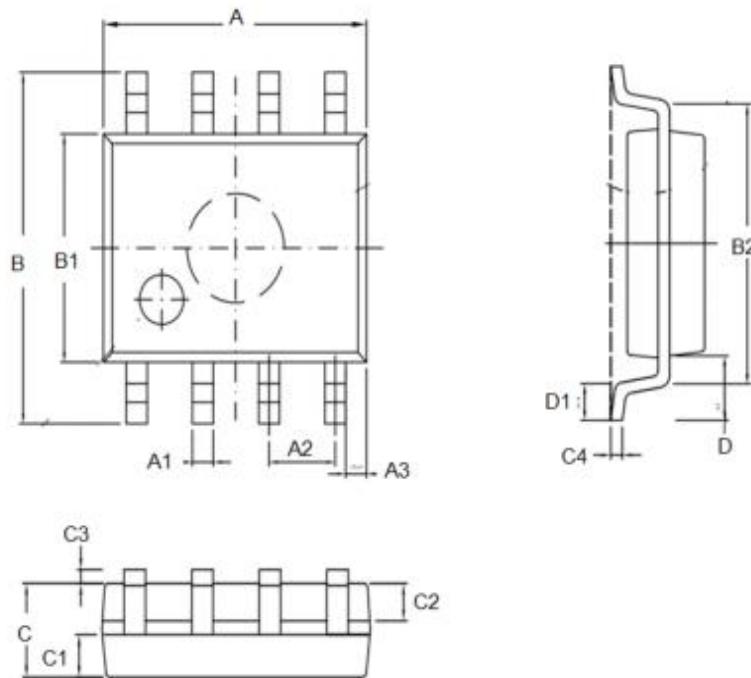


Fig.11 Safe Operating Area

Fig.12 ID vs. Case Temperature^④



•SOP-8 Package Outline



SYMBOL	min	TYP	max	SYMBOL	min		max
A	4.80		5.25	C	1.30		1.75
A1	0.37		0.49	C1	0.55		0.75
A2		1.27		C2	0.55		0.65
A3		0.41		C3	0.05		0.20
B	5.80		6.20	C4	0.10	0.20	0.23
B1	3.80		4.10	D		1.05	
B2		5.00		D1	0.40		0.62

**Note:**

- ① Pulse : VGS=+20V/-20V, Duty cycle=50%, Tj=175 °C, t=1000 hours; For DC , the following test conditions can be passed: VGS=+20V/-10V, Tj=175 °C, t=1000 hours;
- ② Pulse : VGS=+20V/-20V, Duty cycle=50%, Tj=175 °C, t=1000 hours; For DC , the following test conditions can be passed: VGS=-20V/+10V, Tj=175 °C, t=1000 hours;
- ③ Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;
- ④ Practically the current will be limited by PCB, thermal design and operating temperature. VGS=10V (N channel)/-10V(P channel).

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Revision History

Version	Date	Change
A	2021.10.16	NEW
B	2021.10.13	Modified the ID curve
C	2023.11.1	Modified the ID curve